

IUCrJ

Volume 7 (2020)

Supporting information for article:

High-resolution cryo-EM reconstructions in the presence of substantial aberrations

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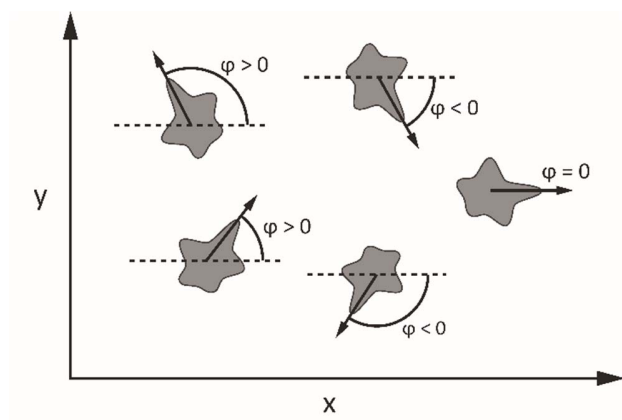


Figure S1 Definition of the orientation angle φ for particles coming from the same projection. This angle is not affected by forces generating preferred orientation in the typical setup of the sample grid being perpendicular to the beam.